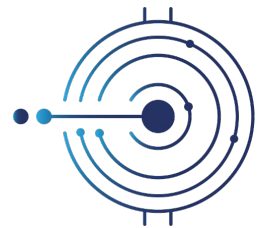


Josephson Junctions Measures

Substrates #07, #11

february 2022



DART
WARS



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substrates

Substrate #07:

- run 1 (no markers)
 - oxidation pressure: $1.36 \cdot 10^{-3}$ mTorr
 - oxidation time: 742 s
 - oxidation process: ?
- } $p^{1/2} \cdot t \text{ [mTorr} \cdot \text{s]} = 27.37$

Substrate #11:

- run 4 (with markers)
 - oxidation pressure: $9.41 \cdot 10^{-4}$ mTorr
 - oxidation time: 2 677 s
 - oxidation process: ?
- } $p^{1/2} \cdot t \text{ [mTorr} \cdot \text{s]} = 82.12$

rate ~ 1/3

Substrates #02 and #05 had the same oxidation parameter and we expected to observe $R_{\#02} = R_{\#05}$.

→ Do we expect to observe $R_{\#07} < R_{\#11}$?

substrates

One substrate consists in **12 devices** (A,-,L) with **14 arrays of Josephson junctions** (20 overall) each.

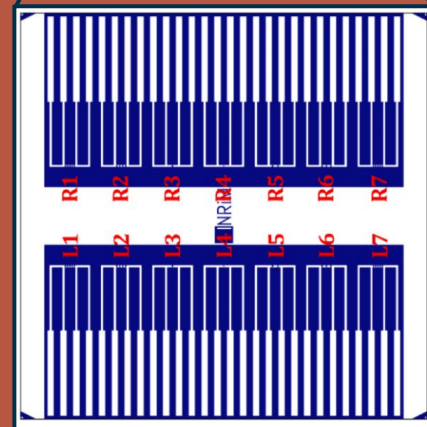
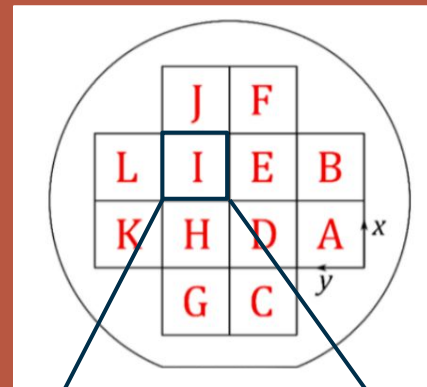
→ 168 measures of resistance for each substrate

junctions #	5	4	1	short	2	3	5
array ID	L1/R1	L2/R2	L3/R3	L4/R4	L5/R5	L6/R6	L7/R7

The short resistance (L4/R4) is required to compute the parasitic impedance introduced by the conductive trails.

series R_{par}	110/250	138/250	222/250	1	194/250	166/250	110/250
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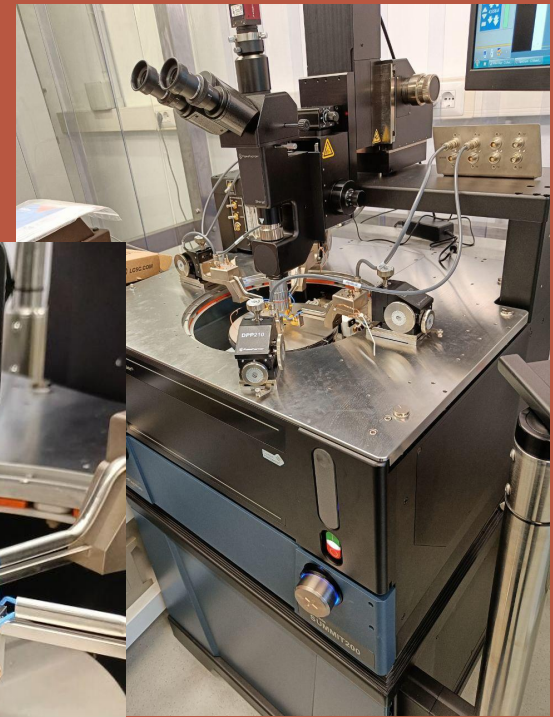
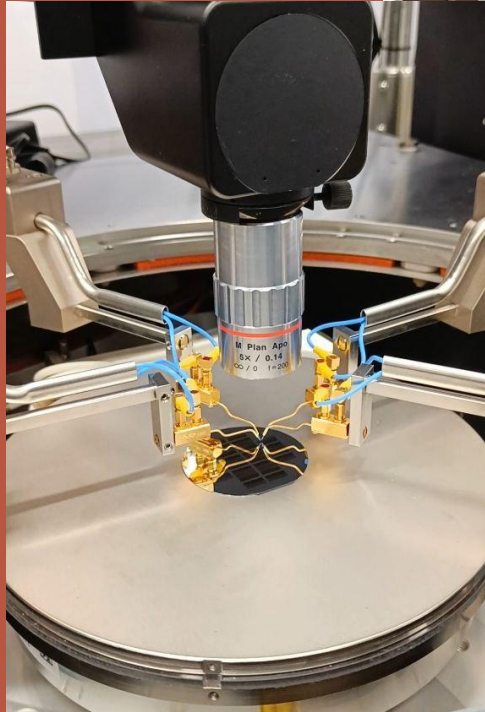
Of course, these factors depend on the junctions #.
We used them to correct the resistance measures.



the measurement

4 terminal sensing measurement
→ current sweep up to 10 μA , with a
0.1 μA step.

The data taking has been improved.
Now the procedure is less time consuming
than it was before ($\sim 2\text{h}$ / substrate).

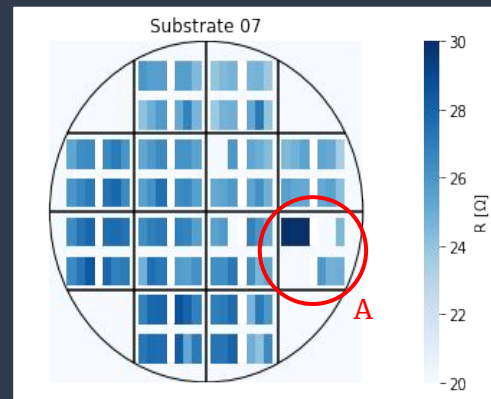
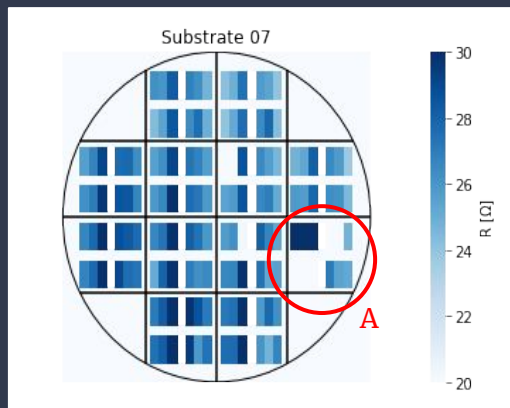
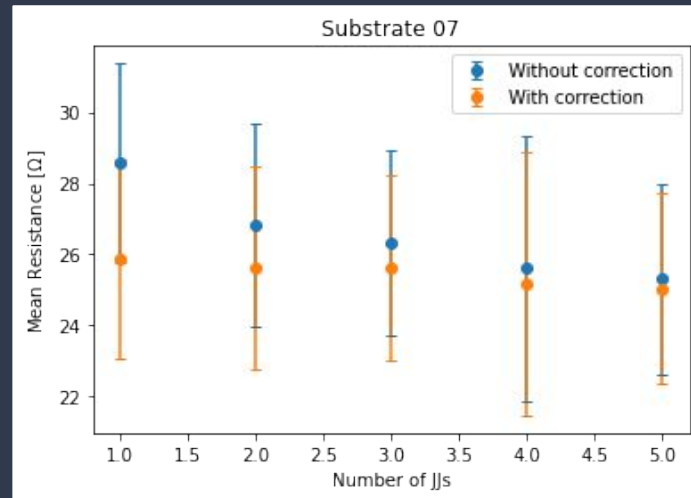


Substrate #07

resistance correction

The correction works!

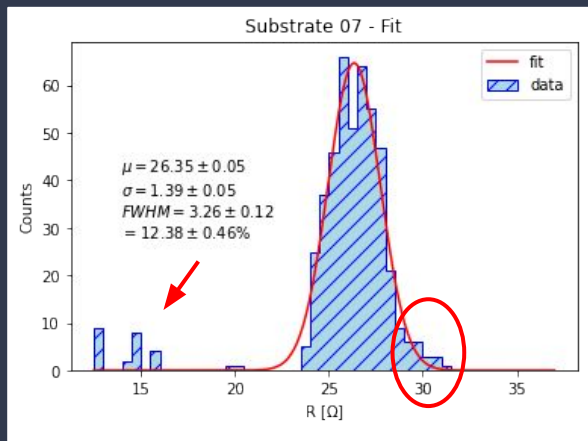
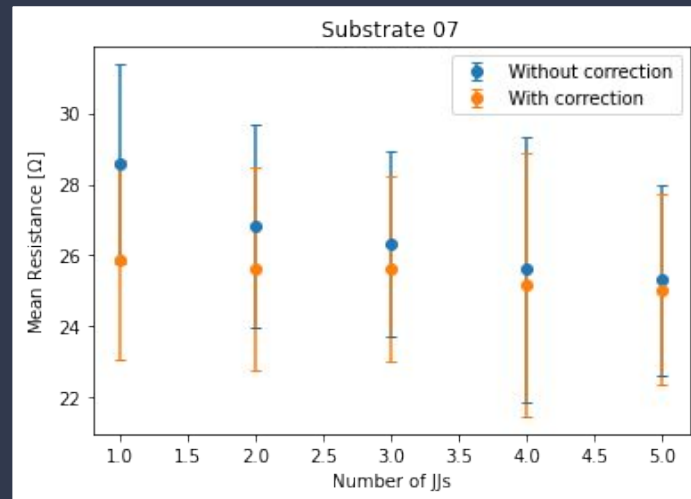
But some devices (A,D,E) show sparse low resistances. In addition, **the device A is partially faulty** and some of its arrays (R1, R2, R3) show open circuit properties.



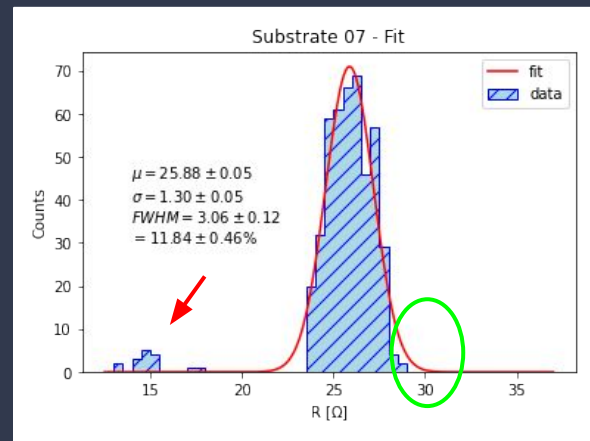
resistance correction

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But some devices (A,D,E) show sparse low resistances. In addition, **the device A is partially faulty** and some of its arrays (R1, R2, R3) show open circuit properties.

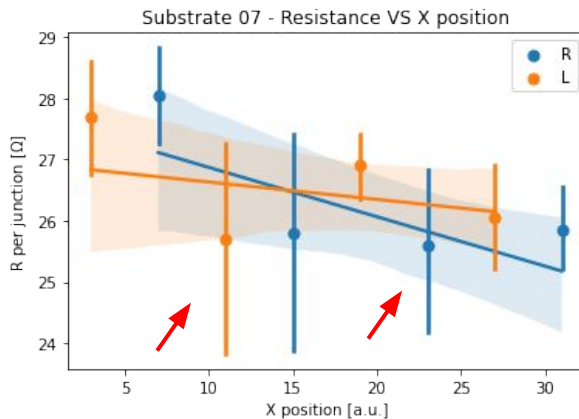
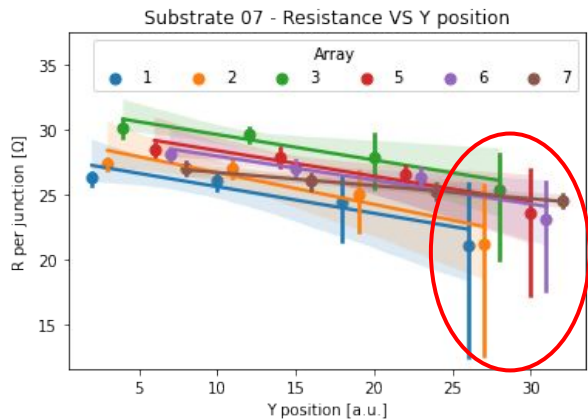
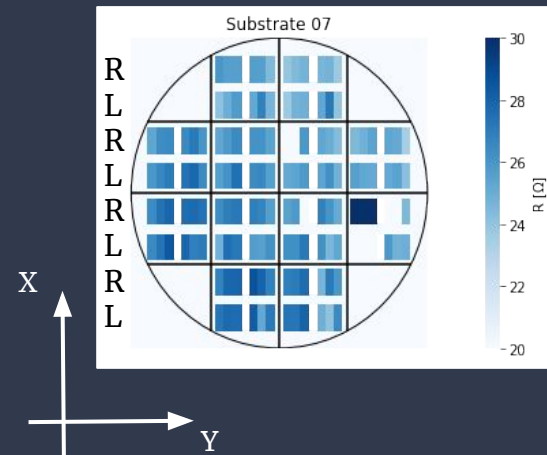


correction



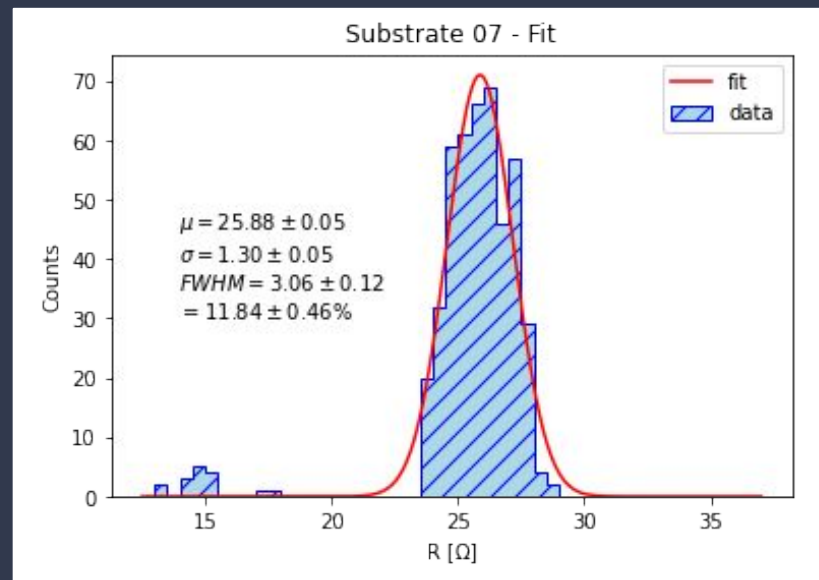
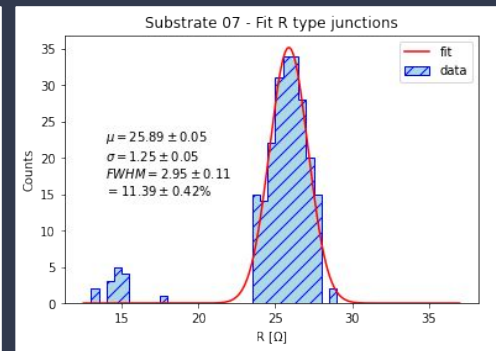
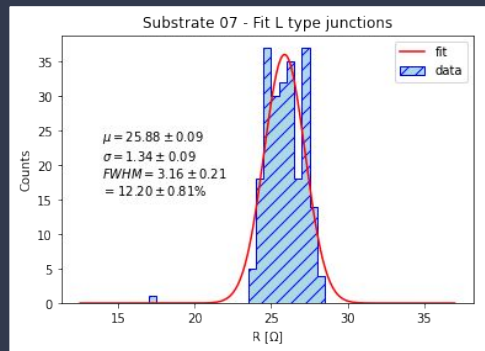
substrate gradients

Both the gradients are descending.
The wide dispersions are due to the faulty arrays.



average resistance

Substrate #07		
	R	ΔR
type L	25.88 Ω	3.06 Ω (11.84%)
	25.88 Ω	3.16 Ω (12.20%)
	25.89 Ω	2.95 Ω (11.39%)

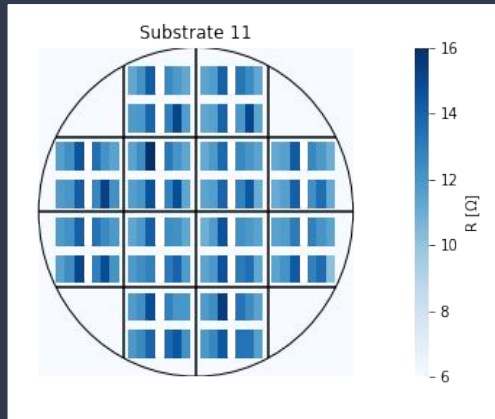
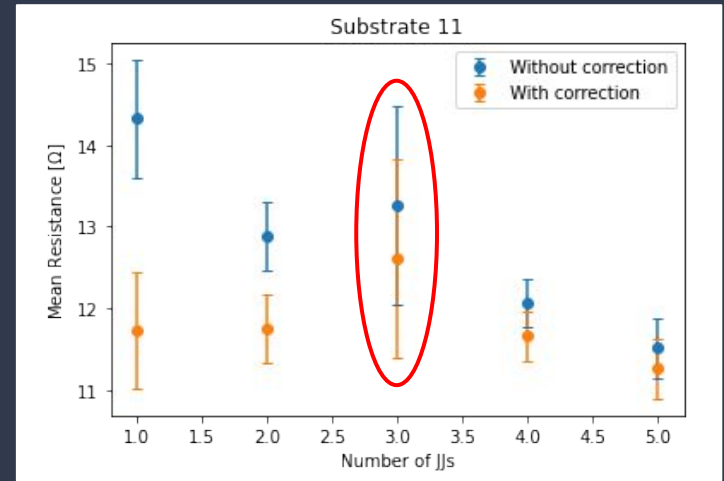


Substrate #11

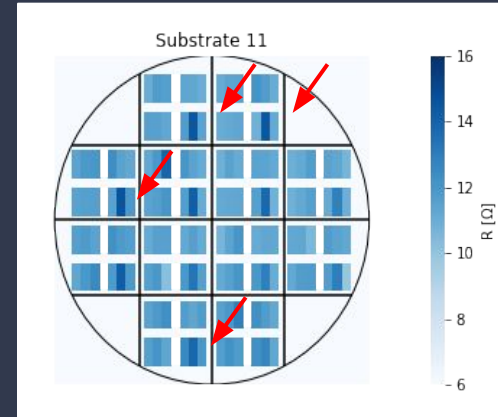
resistance correction

The correction works!

But the **arrays with 3 junctions** seem to have a very wide distribution...



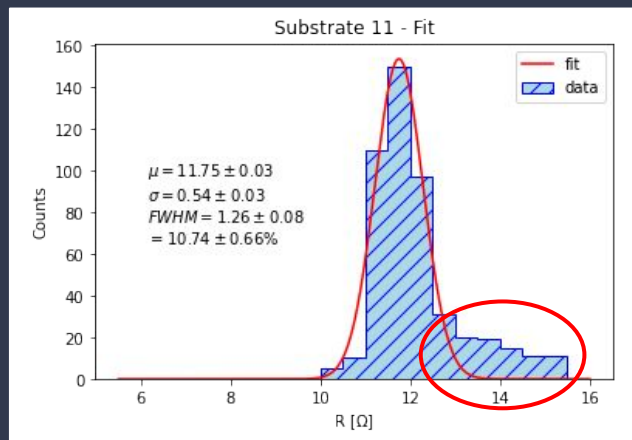
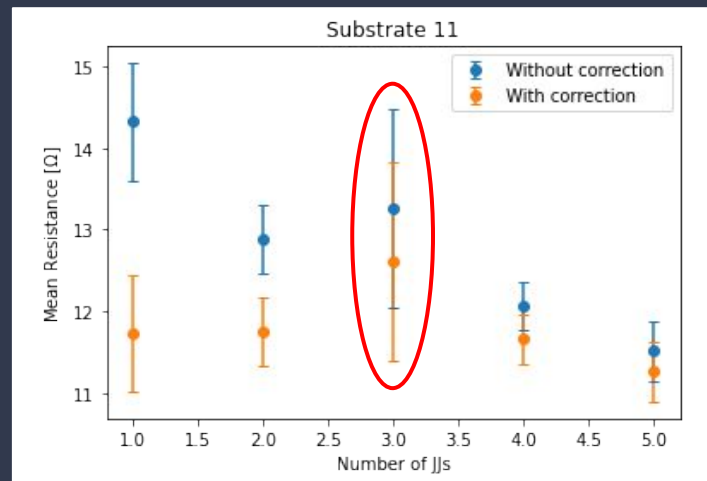
correction



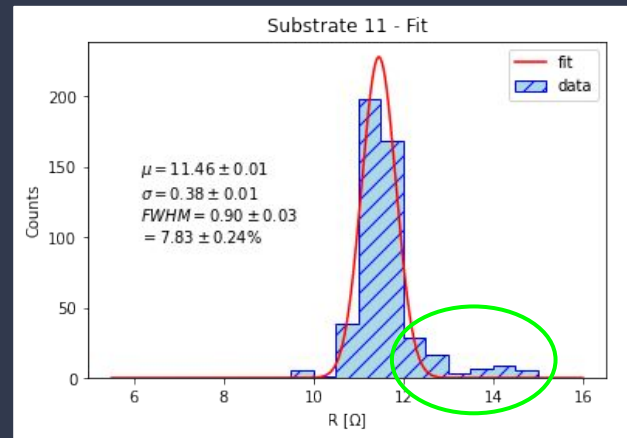
resistance correction

The correction works!

But the arrays with 3 junctions seem to have a very wide distribution...



correction

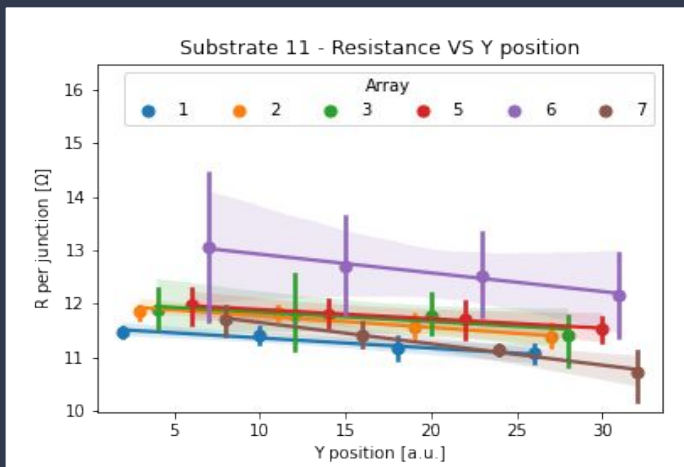
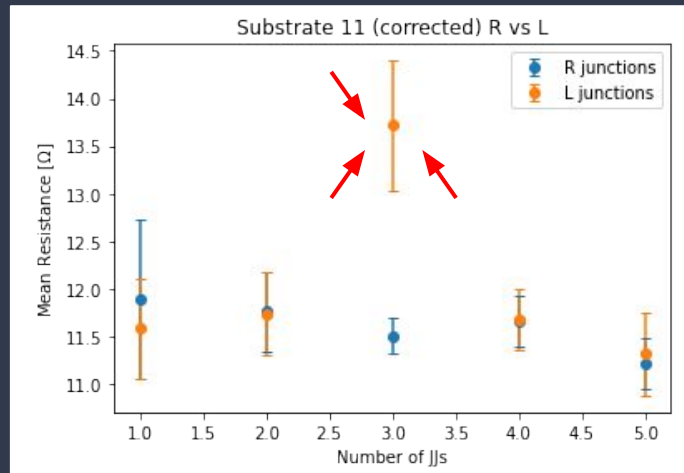


the L6 problem

In details, we observe that the **L6** triple junction arrays show a way higher resistance value.

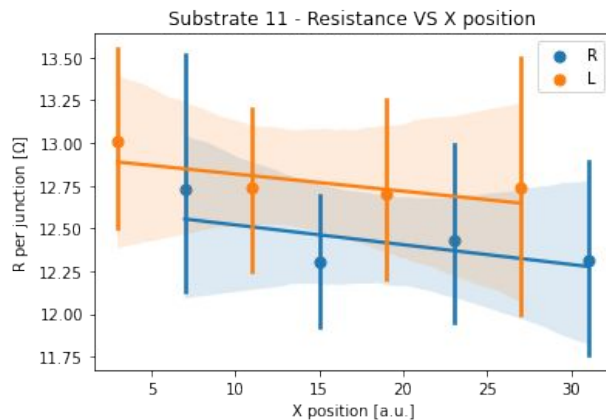
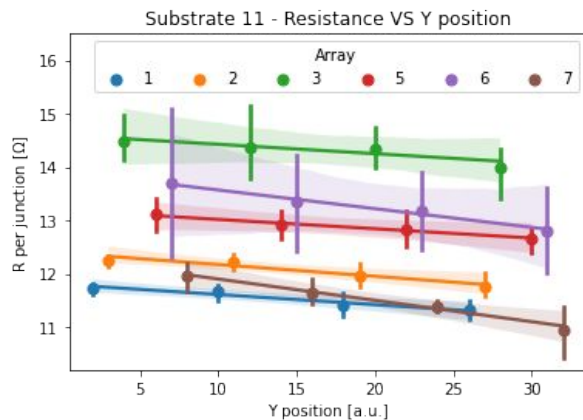
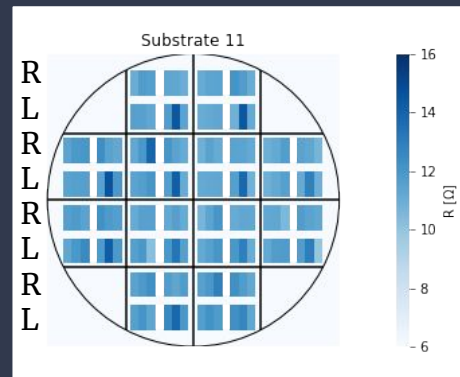
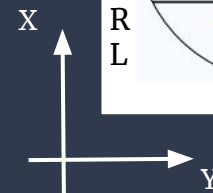
We can point out this anomaly also studying the **gradient on the y direction** of the substrate.

(This is the corrected plot that highlights the difference shifting the offsets of the lines)



substrate gradients

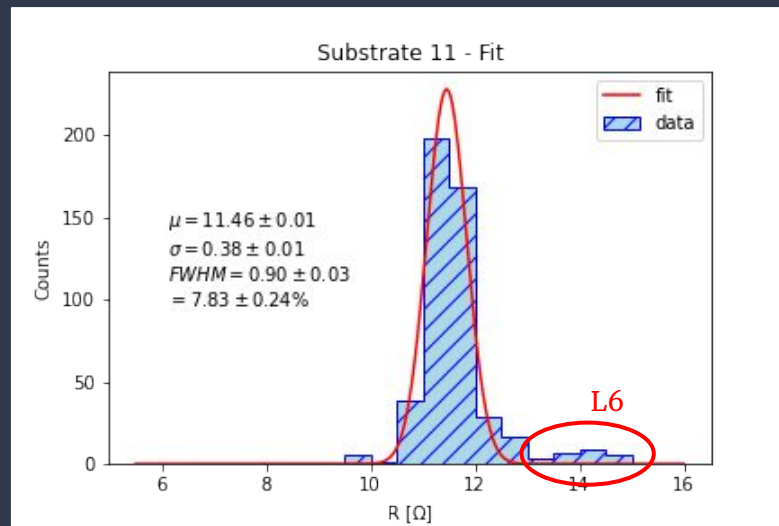
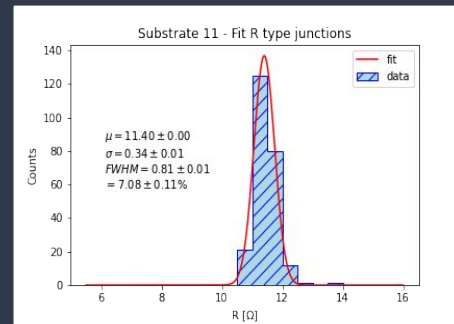
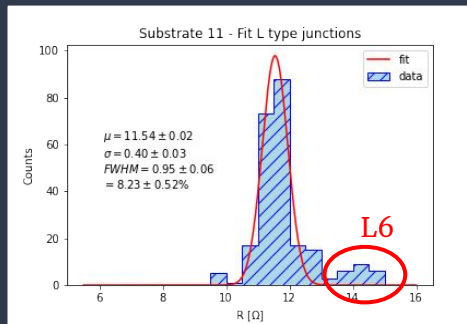
Both the gradients are slightly descending.



average resistance

Substrate #11		
	R	ΔR
	11.46 Ω	0.9 Ω (7.83%)
type L	11.54 Ω	0.95 Ω (8.23%)
type R	11.40 Ω	0.81 Ω (7.08%)

The small amount of counts in the **right tail** of the distribution are caused by the left component (more precisely by **L6**).



substrates comparison

The substrate #07:

- shows an average resistance of $\sim 26 \Omega$ while the substrate #11 is $\sim 11 \Omega$.
 - has a more broadened resistance distribution.
 - has a steeper descending gradient on both x and y directions.
-

With respect to the substrates #02 and #05:

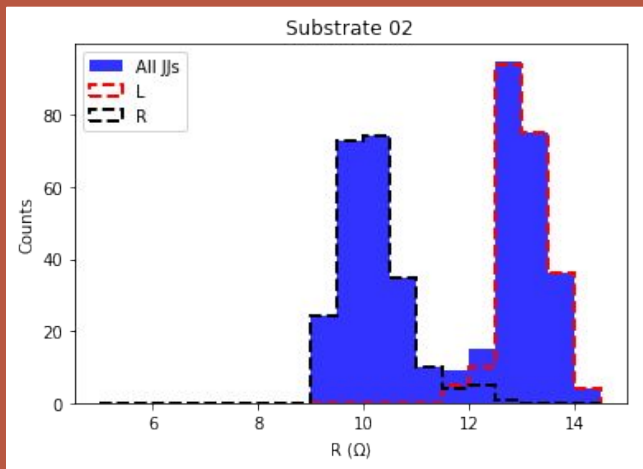
- The L and R resistances are equally distributed around the same substrate-average-value.
- The new wafers show a steeper gradient on y direction and a gradient on the x direction which is now shared by both L and R type of junctions.

substrates comparison

With respect to the substrates #02 and #05:

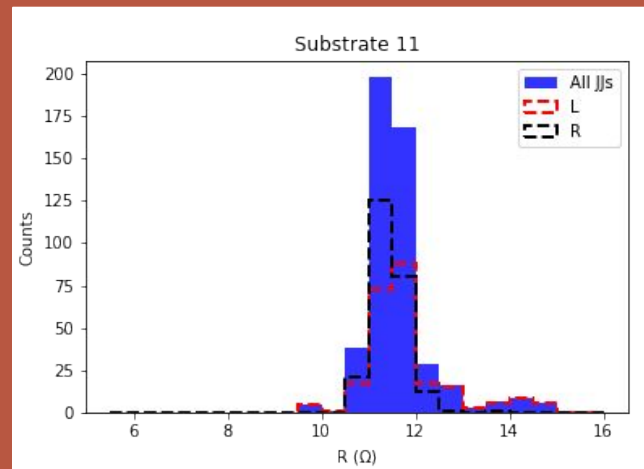
- The L and R resistances are equally distributed around the same substrate-average-value.
- The new wafers show a steeper gradient on y direction and a gradient on the x direction which is now shared by both L and R type of junctions.

before



vs

now

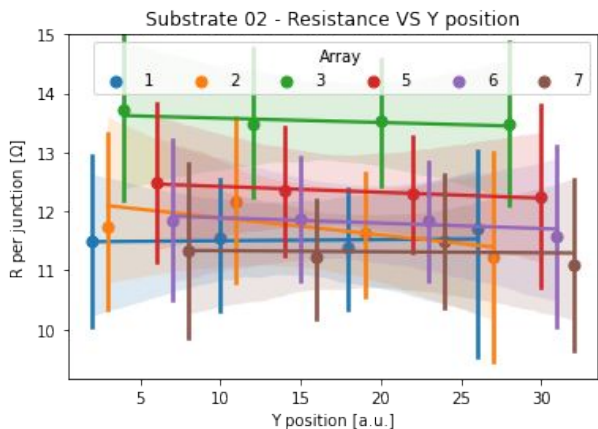


substrates comparison

With respect to the substrates #02 and #05:

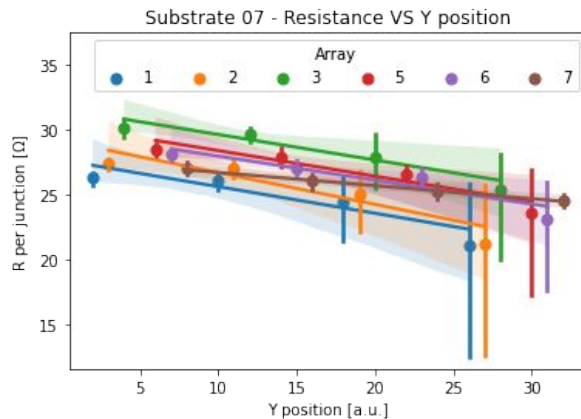
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before



vs

now

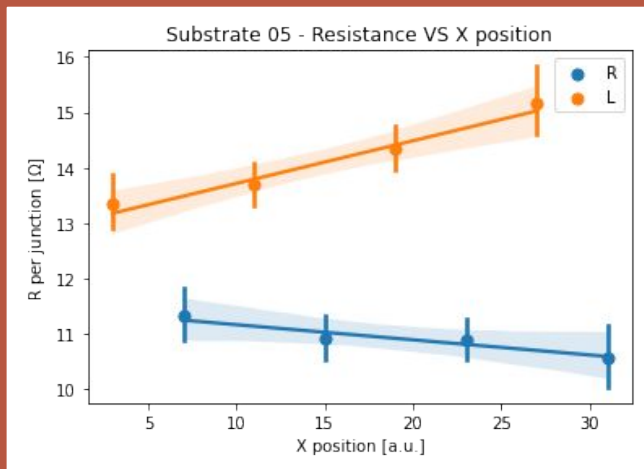


substrates comparison

With respect to the substrates #02 and #05:

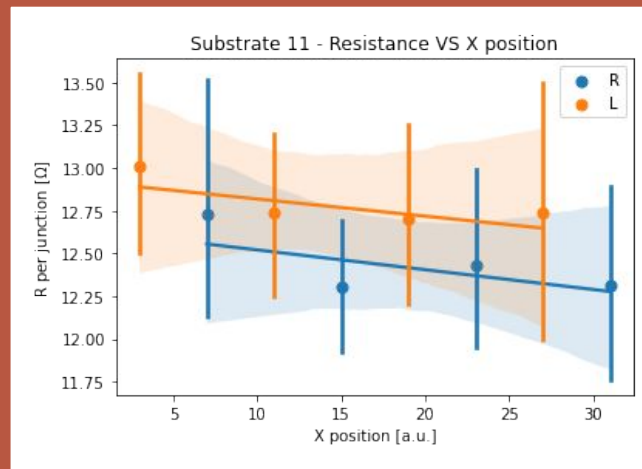
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before



vs

now



Backup slides

